Search Note	es .

Application/Control No.	Applicant(s)/Patent under Reexamination
10/065,566	CHANG, YI-CHEN
Examiner	Art Unit
Amare Mengistu	2673

	SEAR	CHED	
Class	Subclass	Date	Examiner
Up date	searched	2/27/2006	АМ
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INT	INTERFERENCE SEARCHED				
Class	Subclass Date Examiner				

DATE 2/27/2006	AM
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